GL13R50-8

GL Silicon N-Channel Power MOSFET

V_{DSS}	500	V
I_D	1	A
P_D	1	W
$R_{DS(ON)TYP}$	10	Ω

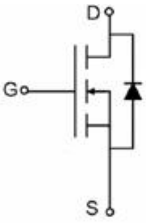
General Description:

GL13R50-8, the silicon N-channel Enhanced VDMOSFET is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is SOP-8, which accords with the RoHS standard.

SOP-8

Features:

- Fast Switching
- Low Gate Charge
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test



Applications:

- Load switch
- Power management

Absolute (Tc=25℃ unless otherwise specified):

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	500	V
I_D	Continuous Drain Current	1	A
	Continuous Drain Current T_C = 100 °C	0.65	A
I_{DM} [a1]	Pulsed Drain Current	4	A
V_{GS}	Gate-to-Source Voltage	±25	V
d_v/d_t [a3]	Peak Diode Recovery dv/dt	5.0	V/ns
P_D	Power Dissipation	1	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, −55 to 150	℃
T_L	Maximum Temperature for Soldering	300	℃

Electrical Characteristics (Tc= 25℃ unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	V_{GS}=0V,I_D=-250μA	500	550	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	I_D=-250uA,Reference25℃	--	0.1	--	V/℃
I_{DSS}	Drain to Source Leakage Current	V_{DS}=500V,V_{GS}=0V,T_a=25℃	--	--	1	μA
		V_{DS}=400V,V_{GS}=0V,T_a=125℃	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	V_{GS}=+20V	--	--	1	μA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	V_{GS}=-20V	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)1}$	Drain-to-Source On-Resistance	V_{GS}=10V,I_D=0.5A	--	--	16	Ω
$R_{DS(ON)2}$	Drain-to-Source On-Resistance	V_{GS}=4.5V,I_D=0.4A	--	--	17	Ω
$R_{DS(ON)3}$	Drain-to-Source On-Resistance	V_{GS}=3V,I_D=0.3A	--	--	18	Ω
$V_{GS(TH)}$	Gate Threshold Voltage	V_{DS}=V_{GS},I_D=250μA	0.5	--	1.5	V
Pulse width tp≤380μs,δ≤2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	V_{DS}=10V,I_D=0.5A	--	1.5	--	S
C_{iss}	Input Capacitance	V_{GS}=0V,V_{DS}=25V f=1.0MHz	--	110	--	pF
C_{oss}	Output Capacitance		--	10	--	
C_{rss}	Reverse Transfer Capacitance		--	1.3	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	I_D=1A,V_{DD}=250V V_{GS}=10V,R_G=3.0Ω	--	6.1	--	ns
t_r	Rise Time		--	6.0	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	18	--	
t_f	Fall Time		--	10	--	
Q_g	Total Gate Charge	I_D=1A,V_{DD}=250V V_{GS}=10V	--	3.0	--	nC
Q_{gs}	Gate to Source Charge		--	0.7	--	
Q_{gd}	Gate to Drain (“Miller”)Charge		--	1.8	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	1	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	4	A
V_{SD}	Diode Forward Voltage	I_S=1A,V_{GS}=0V	--	--	1.5	V
t_{rr}	Reverse Recovery Time	I_S=1A,T_j=25°C	--	250	--	ns
Q_{rr}	Reverse Recovery Charge	dI_F/dt=100A/us,V_{GS}=0V	--	180	--	nC
Pulse width tp≤380μs,δ≤2%						

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	125	°C/W

[a1]: Repetitive rating; pulse width limited by maximum junction temperature

[a3]: I_{SD} =1A,di/dt ≤100A/us,V_{DD}≤BV_{DS}, Start T_J=25°C

Typical Electrical and Thermal Characteristics

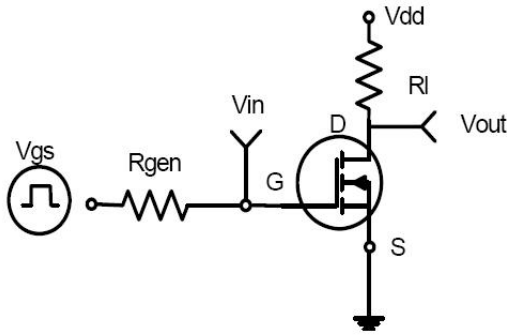


Figure 1:Switching Test Circuit

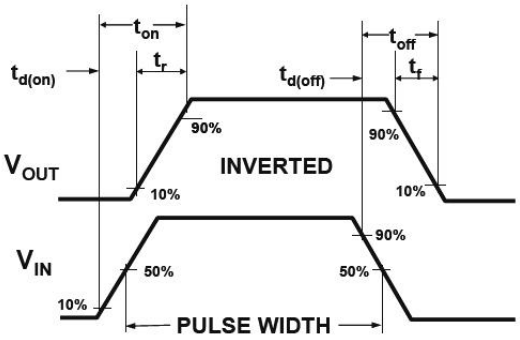


Figure 2:Switching Waveforms

GL Silicon N-Channel Power MOSFET

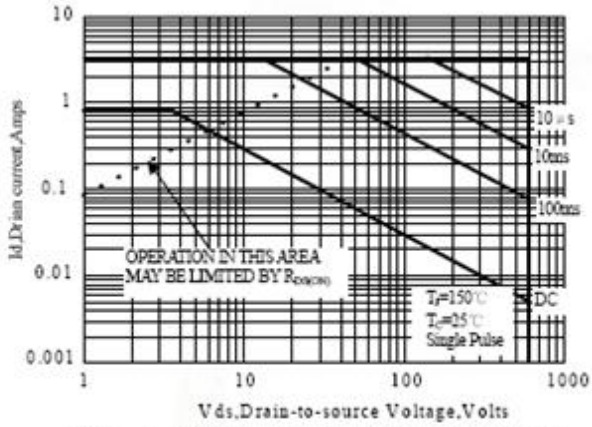


Figure 1 Maximum Forward Bias Safe Operating Area

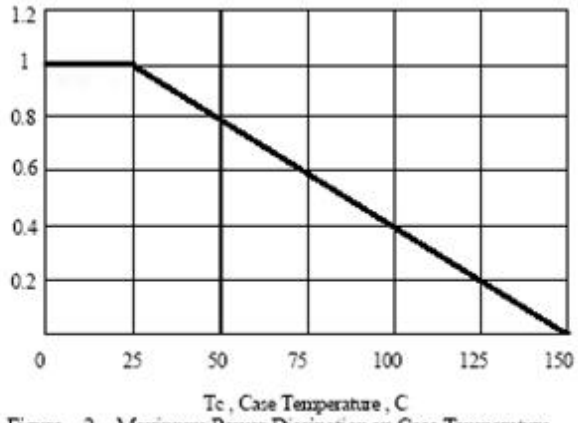


Figure 2 Maximum Power Dissipation vs Case Temperature

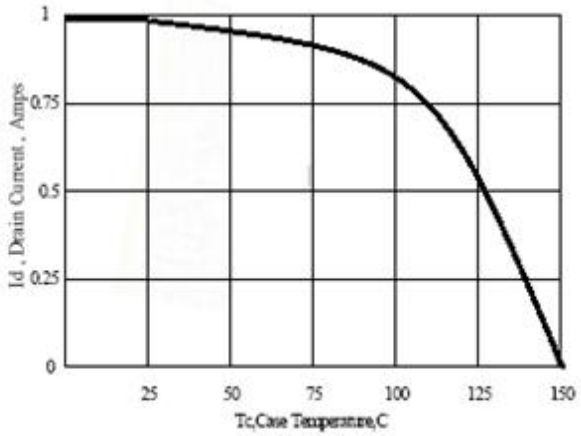


Figure 3 Maximum Continuous Drain Current vs Case Temperature

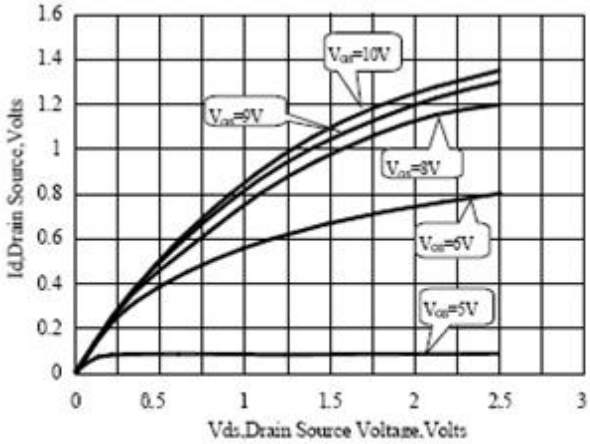


Figure 4 Typical Output Characteristics

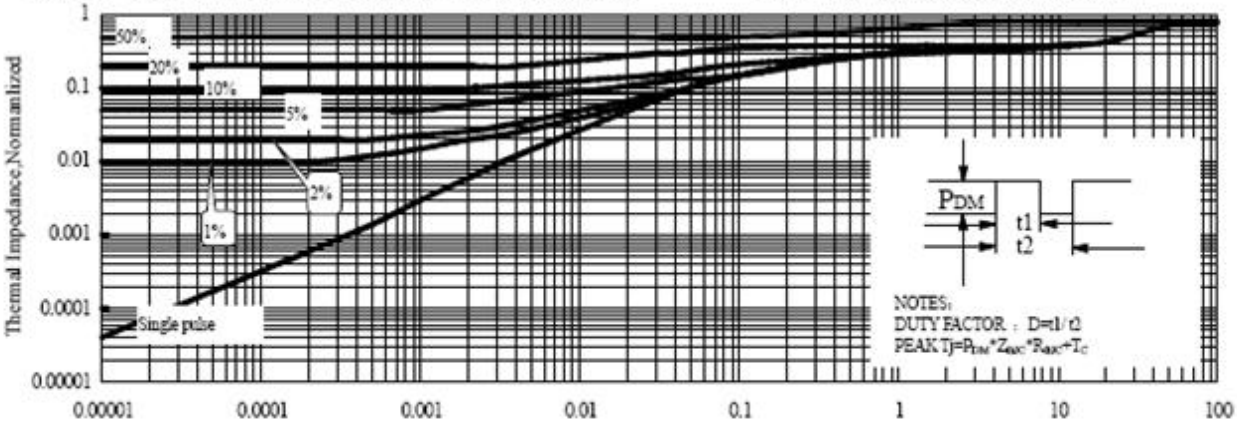


Figure 5 Maximum Effective Thermal Impendance , Junction to Case

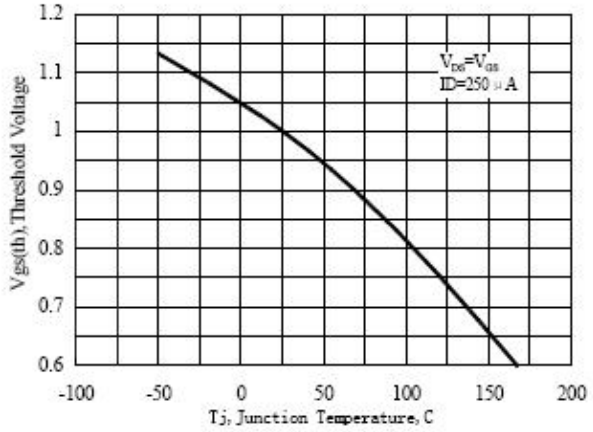


Figure 11 Typical Theshold Voltage vs Junction Temperature

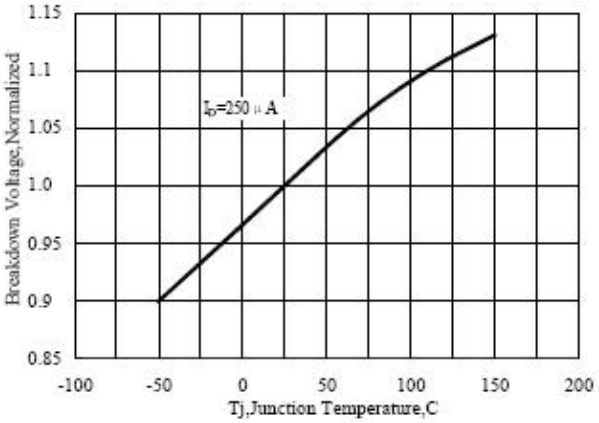


Figure 12 Typical Breakdown Voltage vs Junction Temperature

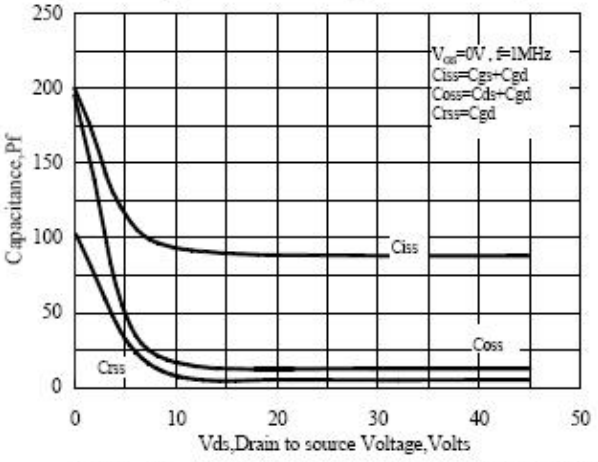


Figure 13 Typical Capacitance vs Drain to Source Voltage

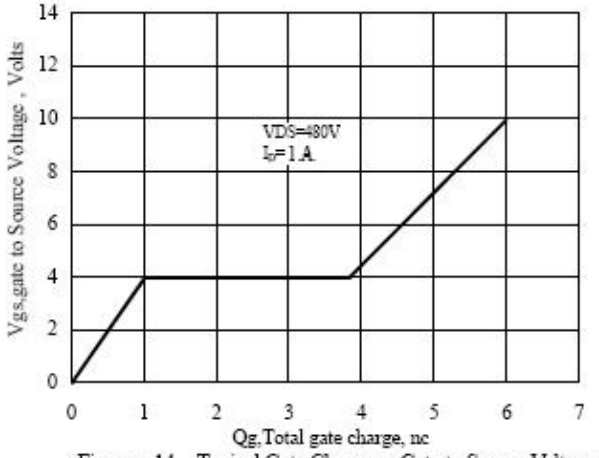


Figure 14 Typical Gate Charge vs Gate to Source Voltage

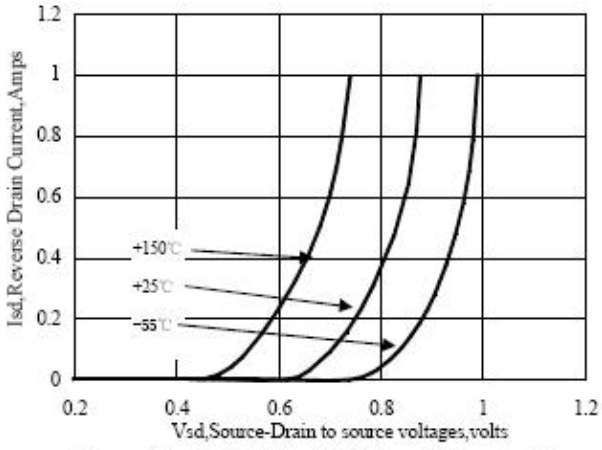


Figure 15 Typical Body Diode Transfer Characteristics

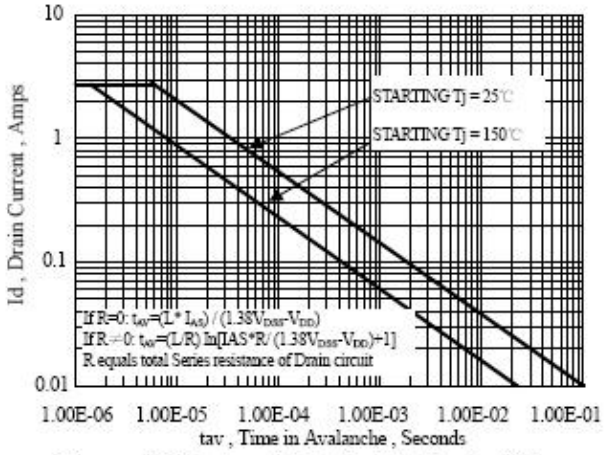


Figure 16 Unclamped Inductive Switching Capability